

TMS 2015

144th Annual Meeting & Exhibition

March 15-19, 2015 • Walt Disney World
Orlando, Florida, USA

Connecting the global minerals, metals, and materials community.



Plan Now to Attend:

Characterization of Minerals, Metals, and Materials

This symposium focuses on the characterization of minerals, metals, and materials and the applications of characterization results on the processing of these materials. Subjects include, but are not limited to, extraction & processing of various minerals, metals (including ferrous, non-ferrous and precious metals and alloys, etc), metal-matrix composites, ceramic and refractories, polymers, biomaterials, carbon, electronic, magnetic and optical materials, high-temperature materials, newly developed advanced materials, gaseous, liquid and solid pollutants, recycling, and advanced characterization techniques, etc.

Areas of interest include, but are not limited to:

- Techniques for characterizing materials across a spectrum of systems and processes
- Characterization of mechanical and physical properties of materials
- Characterization of processing of materials
- Characterization of structure and properties of materials
- Emerging characterization techniques
- Characterization of extraction and processing, which include process development and analysis of various processes
- Characterization of microstructure and properties of materials, which include: process integration, characterization of thin films (semi-conductor), micro-texture, computer tomography (CT), x-ray tomography (XRT), in-situ microscopy, nano-scale TEM, FIB techniques, and GeoMet

Sponsored by:

- TMS Extraction & Processing Division
- Materials Characterization Committee

Organized by:

John Carpenter, Los Alamos National Laboratory (USA)
Chenguang Bai, Chongqing University (China)
Juan Pablo Escobedo, University of New South Wales (Australia)
Jiann-Yang Hwang, Michigan Technological University (USA)
Shadia J. Ikhmayies, Al Isra University (Jordan)
Bowen Li, Michigan Technological University (USA)
Sergio Neves Monteiro, Military Institute of Engineering, IME, Materials Science Department (Brazil)
Zhiwei Peng, Michigan Technological University (USA)
Mingming Zhang, ArcelorMittal (USA)

**For more information on how
to participate, visit:**

www.tms.org/TMS2015

Questions? Contact programming@tms.org